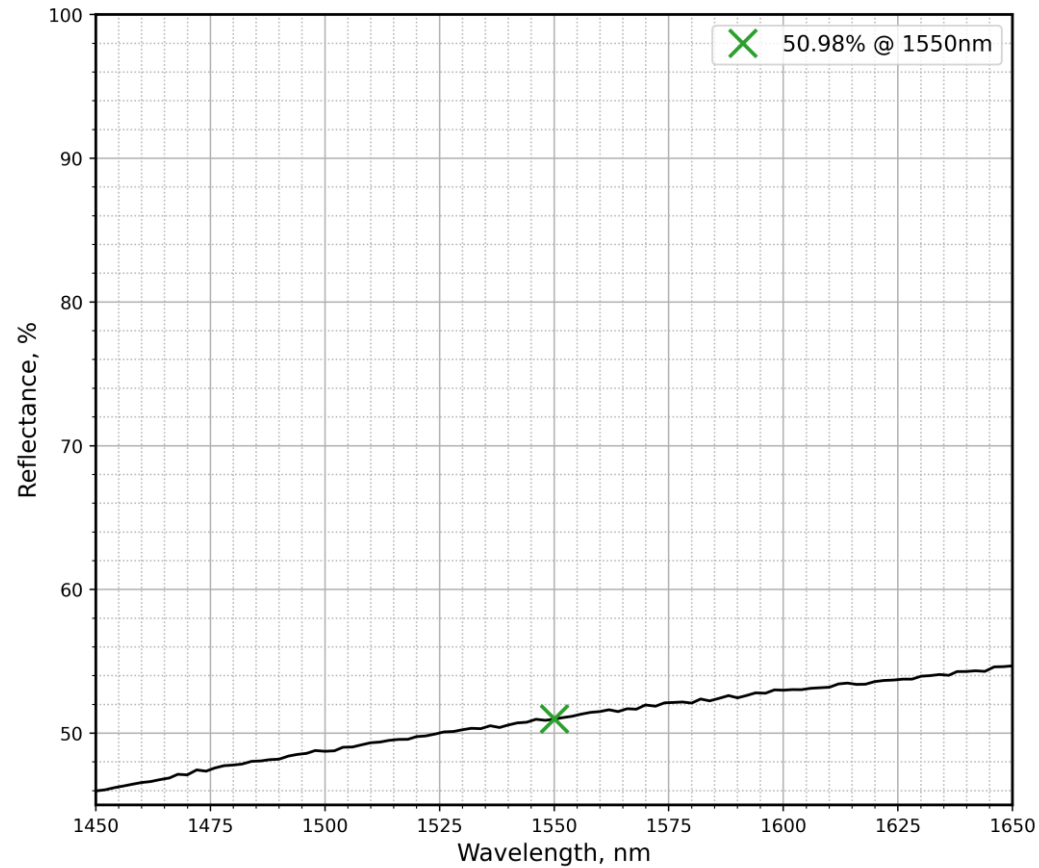


S1: (arrow marks) $R_s=50\% \pm 3\%$ & $R_p=50\% \pm 3\%$ & $|R_s - R_p| < 3\%$ @ 1550 nm, AOI=45 deg
S2: (wedge) $AR_{sp} < 0.7\%$ @ 1550 nm, AOI=45 deg



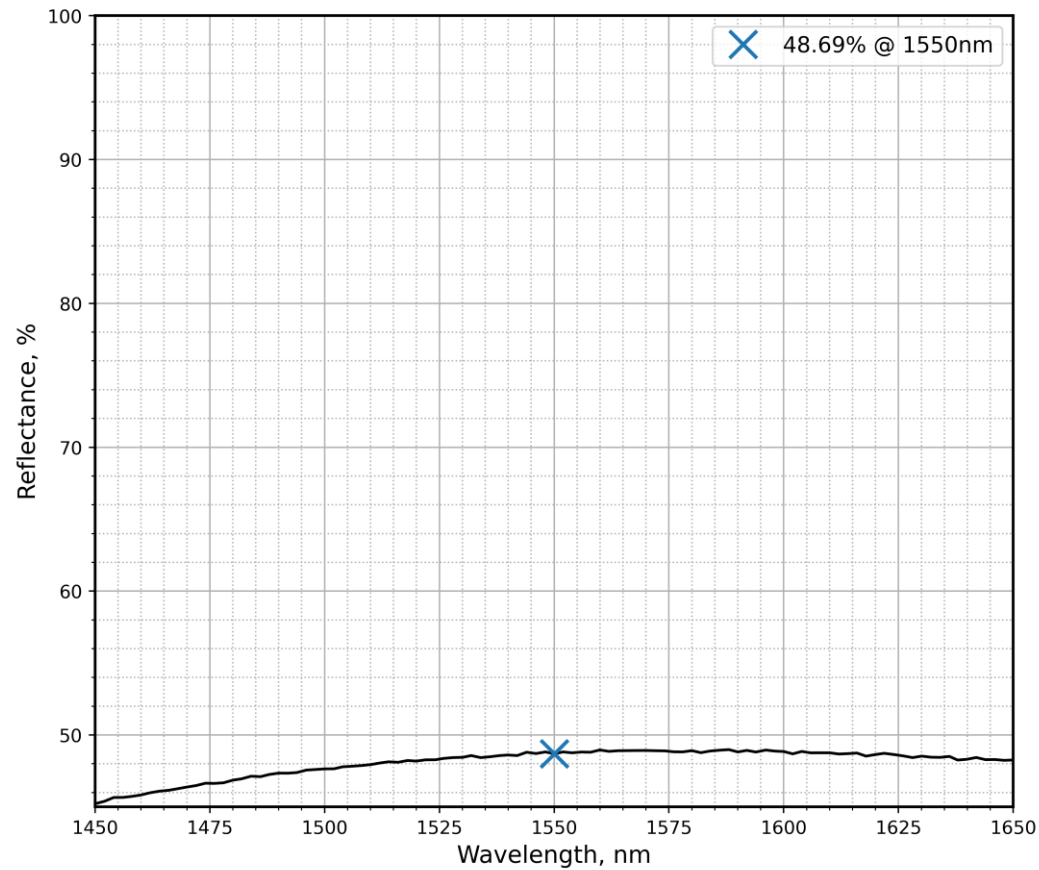
PO4954 Rs i45

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS:

S1: (arrow marks) $R_s=50\% \pm 3\%$ & $R_p=50\% \pm 3\%$ & $|R_s - R_p| < 3\%$ @ 1550 nm, AOI=45 deg
S2: (wedge) $AR_{sp} < 0.7\%$ @ 1550 nm, AOI=45 deg



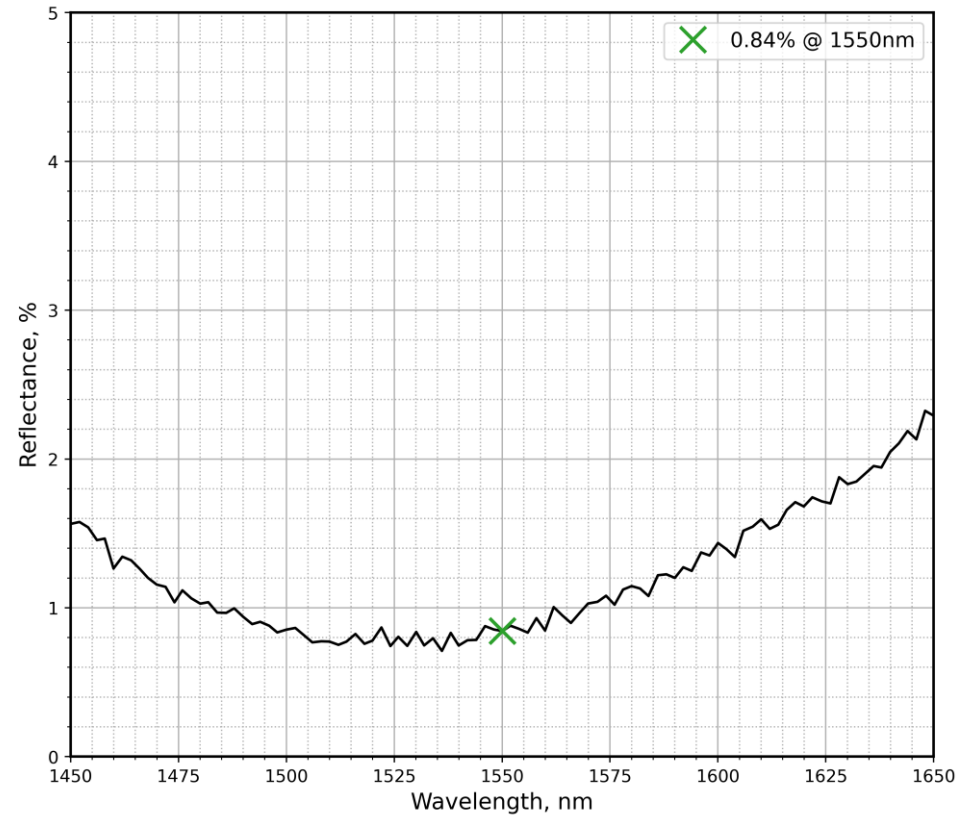
PO4954 Rp i45

Fig. 2.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS:

S1: (arrow marks) $R_s=50\% \pm 3\%$ & $R_p=50\% \pm 3\%$ & $|R_s - R_p| < 3\%$ @ 1550 nm, AOI=45 deg
 S2: (wedge) $AR_{sp} < 0.7\%$ @ 1550 nm, AOI=45 deg



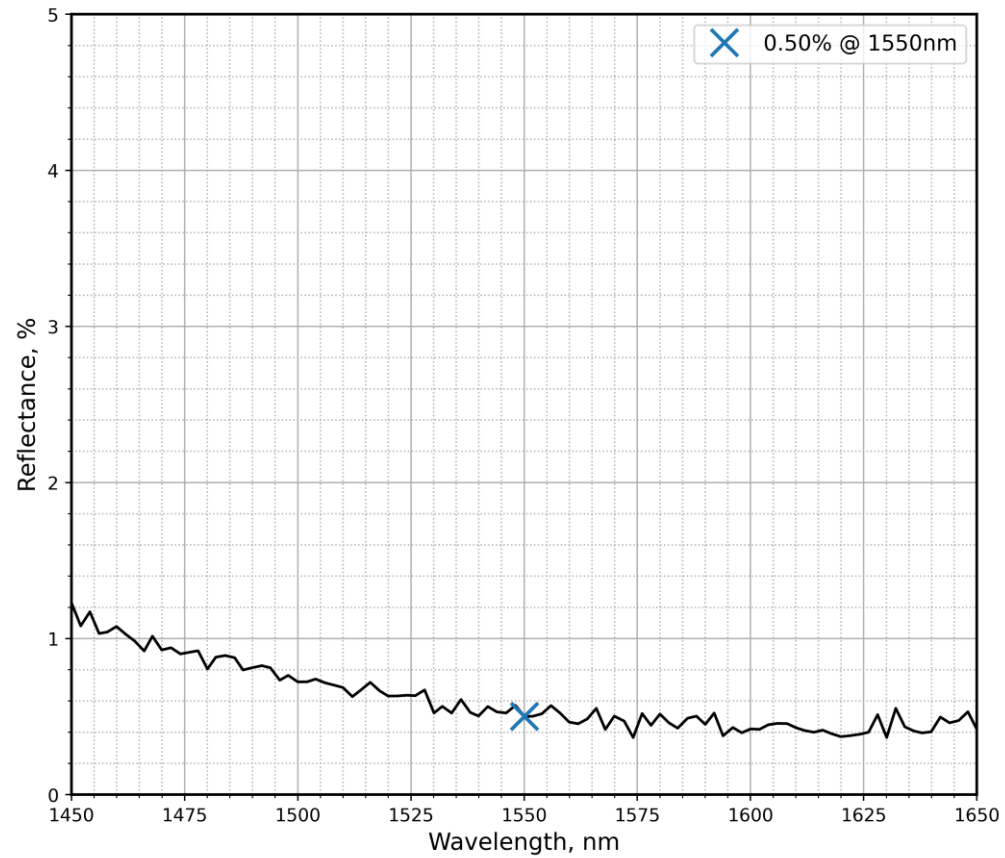
PO4954 Rs i45

Fig. 3.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: $\pm 0.25\%$

S1: (arrow marks) $R_s=50\% \pm 3\%$ & $R_p=50\% \pm 3\%$ & $|R_s - R_p| < 3\%$ @ 1550 nm, AOI=45 deg
 S2: (wedge) $AR_{sp} < 0.7\%$ @ 1550 nm, AOI=45 deg



PO4954 Rp i45

Fig. 4.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: